

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		"20020070738"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
		250/492.2	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
		250/492.1	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
		250/491.1	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
		(electron adj beam) and semiconductor and repair and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
		"21" and photoresist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
		"21" and photoresist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
		((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
		(electron adj beam) and (remove same residue same beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
		("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PNL	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39

	"20020070738"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	S57 and "250"/\$.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	S57 and ("324"/\$.ccls.)	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	(electron adj beam) and (remove same residue same beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	S106 and "250"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	250/307	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	(US-20020070738-\$ or US-20020123818-\$ or US-20030132765-\$ or US-20040018449-\$ or US-20040021076-\$ or US-20040031932-\$ or US-20040167656-\$). did. or (US-4417203-\$ or US-5412210-\$ or US- 5543357-\$ or US- 5637186-\$ or US- 5866904-\$ or US- 6005400-\$ or US- 6124598-\$ or US- 6150185-\$ or US- 6232787-\$ or US- 6323484-\$ or US- 6407373-\$ or US- 6451621-\$ or US-	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39

	6541770-\$ or US- 6559662-\$ or US- 6566655-\$ or US- 6579733-\$ or US- 6583414-\$ or US- 6614050-\$ or US- 6614244-\$ or US- 6617087-\$ or US- 6683308-\$ or US- 6723987-\$ or US- 6753194-\$ or US- 6768324-\$ or US- 6777677-\$ or US- 6828554-\$.did.				
	250/310	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	"6559662"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	"6559662"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	(electron adj beam) and (correction adj process\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39

	(electron adj beam) and default and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	250/310	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	250/311	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and scribe	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	"20040031932"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	(electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	(electron adj beam) and default and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	S126 or S127 or S128 or S129 or S130 or S131 or S132 or S133 or S134 or S135 or S136 or S137 or S138 or S139	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	"1" or "2" or "3" or "5" or "7" or "9" or "10" or "12" or "13" or "14" or "15" or "16" or "17" or "18" or "19" or "20"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39

	("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	(electron adj beam) and semiconductor and repair and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	(electron adj beam) and (remove same residue same beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	"20030146381"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	"20030146381"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	324/ 751	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	(electron adj beam) and default and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	(electron adj beam) and semiconductor and fault and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	(electron adj beam) and semiconductor and repair and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	324/ 751	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	324/ 537	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	250/ 492.22	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39

	250/492.21	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	S204 S205 and (current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides)	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	250/307	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	S201 S202	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	250/492.21	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	250/492.2	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	250/311	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	(electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	250/310	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	(electron adj beam) and semiconductor and fault and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38

	(electron adj beam) and semiconductor and repair and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	(electron adj beam) and (remove same residue same beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and scribe	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (yamada.in.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	324/522	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	324/500	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	(electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	("4417203" "4980639" "5680056" "5804980" "5877498" "6005400" "6177681" "6232787" "6323484").PN.	USPAT	OR	OFF	2008/08/26 17:39

		"6559662"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
		"20020070738"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
		(electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
		(electron adj beam) and (correction adj process\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
		(electron adj beam) and semiconductor and fault and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
		((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (yamada.in.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
		((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
		S140 and photoresist	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
		"20030146381"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
		"20040031932"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38

	((electron adj beam\$1 and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1 and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides) and (bias and (surface same (charge or precharge)))) and (250/310 or 250/307)	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	((current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides) and (bias and (surface same (charge or precharge))))	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	S204 S205 and ((current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides))	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	"kadyshvitch.in."	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	S140 and ("324"/\$. ccls.)	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	"6559662"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39

	S97 or S98 or S99 or S95 or S96 or S100 or S101 or S102 or S103 or S104 or S105 or S106 or S107 or S108	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	324/537	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	("4417203" "4980639" "5680056" "5804980" "5877498" "6005400" "6177681" "6232787" "6323484").PN.	USPAT	OR	OFF	2008/08/26 17:39
	(electron adj beam) and default and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	S57 and photoresist	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	S43 or S44 or S45 or S46 or S47 or S48 or S49 or S50 or S51 or S52 or S53 or S54 or S55 or S56	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	(electron adj beam) and semiconductor and fault and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	(electron adj beam) and semiconductor and repair and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39

	(electron adj beam) and (remove same residue same beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	S137 and "250"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	"20020070738"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	S140 and "250"/\$.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	324/ 522	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	"20020070738"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	250/491.1	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	S54 and "250"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	(electron adj beam) and (correction adj process\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38

	S204 S205 and ((current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides) and (bias and surface same (charge or precharge))))	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	(electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	("4417203" "4980639" "5680056" "5804980" "5877498" "6005400" "6177681" "6232787" "6323484").PN.	USPAT	OR	OFF	2008/08/26 17:38
	"6559662"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	"20030146381"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	"20040031932"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39

	(electron adj beam) and semiconductor and repair and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	324/501	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	324/500	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	324/501	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	kadyshevitch.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	"20030146381"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	S39 and "250"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	(electron adj beam) and (correction adj process\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	"20020070738"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	(electron adj beam) and default and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39

	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and scribe	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (yamada.in.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	S204 S205 and (current same (sample or wafer or specimen or target))	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	250/310	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	S204 S205 and (current same (sample or wafer or specimen or target)) and (electron adj beam)	US-PGPUB; USPAT	OR	ON	2008/08/26 17:39
	("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	S106 and "250"/\$.ocls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39

	(electron adj beam) and (correction adj process\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	S23 or S24 or S29 or S30 or S31 or S32 or S34 or S35 or S36 or S37 or S38 or S39 or S40 or S41	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:38
	"21" and photoresist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	250/492.1	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	"kadyshkevitch.in",	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	250/492.22	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	("20030132381" "20030132765" "5162240" "5376215" "5427052" "6306001").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/08/26 17:39
	(electron adj beam) and semiconductor and fault and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	(electron adj beam) and (remove same residue same beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38

	"20030146381"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:38
	S89 and "250"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	(electron adj beam) and (correction adj process\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	(electron adj beam) and default and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	(electron adj beam) and semiconductor and fault and correction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and (electromagnetic or light \$1 or laser) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	((electron adj beam\$1) and (contact adj (hole \$1 or opening\$1))) and auger	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	"6559662"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/26 17:39
	"1" or "2" or "3" or "5" or "7" or "9" or "10" or "12" or "13" or "14" or "15" or "16" or "17" or "18" or "19" or "20"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/08/26 17:38

8/ 26/ 08 6:02:20 PM

C:\Documents and Settings\dvanore\My Documents\EAST\Workspaces\106956201.wsp